

# AgSn/InZnO スペーサーCPP-GMR スピンバルブの磁気抵抗特性

## CPP-GMR spin-valves with AgSn/InZnO spacers

物材機構<sup>1</sup>, <sup>○</sup>中谷 友也<sup>1</sup>, Muftah Al-Mahdawi<sup>1</sup>, 佐々木 泰祐<sup>1</sup>, 桜庭 裕弥<sup>1</sup>, 宝野 和博<sup>1</sup>

NIMS<sup>1</sup>, <sup>○</sup>Tomoya Nakatani<sup>1</sup>, M. Al-Mahdawi<sup>1</sup>, Taisuke Sasaki<sup>1</sup>, Yuya Sakuraba<sup>1</sup>, Kazuhiro Hono<sup>1</sup>

E-mail: nakatani.tomoya@nims.go.jp

Current-perpendicular-to-plane giant magnetoresistance (CPP-GMR) devices with Heusler alloy ferromagnetic layers and a hybrid spacer structure composed of non-magnet/conductive oxide composite exhibit large magnetoresistive (MR) outputs at resistance-area product ( $RA$ )  $\sim 0.1 \Omega \mu\text{m}^2$ , [1] therefore promising for nano-scale magnetic sensor applications such as read sensors for hard disk drives. Here, we report the MR properties of polycrystalline spin-valve devices with  $\text{Co}_2(\text{Mn}_{0.6}\text{Fe}_{0.4})\text{Ge}$  Heusler alloy ferromagnetic layers and a AgSn/InZnO (IZO) bilayer spacer. [2]

Polycrystalline bottom-pinned spin-valves were deposited by magnetron sputtering on thermally oxidized Si substrates coated with a Cu (100 nm)-based bottom electrode. The layer structure is shown in Fig. 1(a). A  $\text{Ag}_{90}\text{Sn}_{10}$ (0.4 nm)/IZO(1.4-1.85 nm) bilayer spacer was used. After annealing at 280 °C for 3 h, the films were patterned to circular pillars with a 120 nm-diameter.

Fig. 1(b) shows the MR ratio ( $\Delta R/R$ ) vs.  $RA$  of the devices with a variation of the IZO thickness. The  $RA$  value increased with increasing IZO thickness. The largest  $\Delta R/R$  of  $\sim 30\%$  was obtained at  $RA \sim 0.1 \Omega \mu\text{m}^2$ , much larger than that of the conventional all-metallic CPP-GMR spin-valves with a AgSn(3.5 nm) spacer ( $\Delta R/R = 14\%$  at  $RA = 0.04 \Omega \mu\text{m}^2$ ). Note that the  $\Delta R/R$  enhancement by the AgSn/IZO spacer was realized even at lower  $RA$  range of  $\sim 0.05 \Omega \mu\text{m}^2$ . As shown in Fig. 1(c), the device resistance in the parallel magnetization configuration ( $R_P$ ) showed a monotonous decrease as temperature was decreased, indicating a metallic conduction in the AgSn/IZO spacer. The large increment of  $\Delta R/R$  with decreasing temperature ( $\Delta R/R = 95\%$  at 5 K) suggests a large increase of the spin polarization of the CMFG Heusler alloy layers at low temperatures.

**References** [1] Nakatani *et al.* Appl. Phys. Express **8**, 093003 (2015). [2] Nakatani *et al.* IEEE Trans. Magn., in press (DOI: 10.1109/TMAG.2017.2753221)

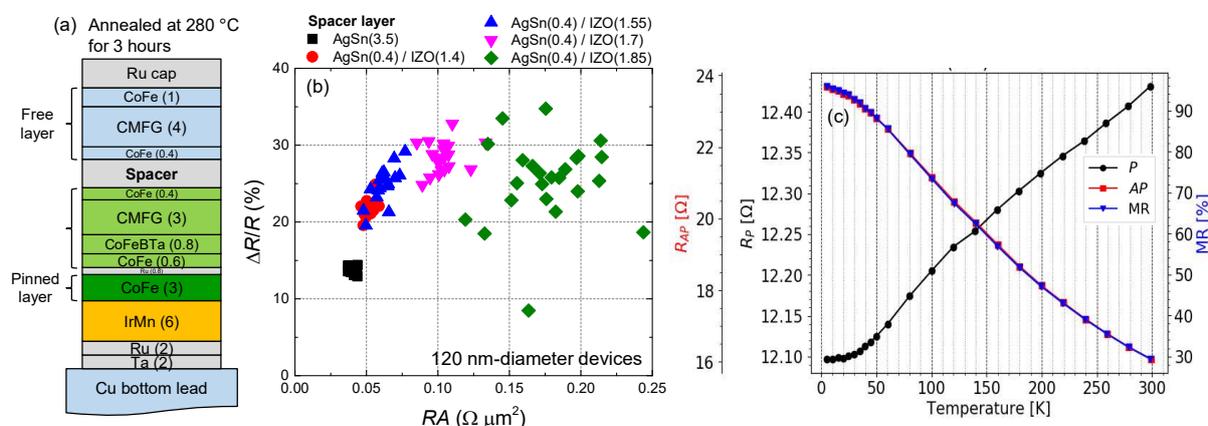


Fig. 1(a) Spin-valve film structure, (b)  $\Delta R/R$  vs.  $RA$  for the AgSn(3.5) and AgSn(0.4)/IZO( $t$ ) spacers, (c) temperature dependences of  $R_P$ ,  $R_{AP}$  and  $\Delta R/R$  for AgSn(0.4)/IZO(1.7) ( $RA = 0.1 \Omega \mu\text{m}^2$ ,  $\Delta R/R = 30\%$ ).